

RELIABILITY DATA

LTM8002 Qualification Data

7/26/2019

• J-STD-020 MSL 3 PRECONDITIONING: 192h +30°C/60%R.H. SOAK, 3x REFLOW AT +260°C PEAK					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES
LTM8002	899 899	1817	1840		0 0
• HIGH TEMPERATURE STORAGE +150°C					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +150°C	NUMBER OF FAILURES
LTM8002	199 199	1817	1840	321.00 321.00	0 0
• TEMP CYCLE FROM -55°C to +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM8002	25 25	1817	1840	50.00 50.00	0 0
• TEMP CYCLE FROM -65°C to +150°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM8002	234 234	1817	1840	237.00 237.00	0 0
• THERMAL SHOCK FROM -55°C to +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM8002	25 25	1817	1840	50.00 50.00	0 0
• THERMAL SHOCK FROM -65°C to +150°C ⁽¹⁾					
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE CYCLES	NUMBER OF FAILURES
LTM8002	234 234	1817	1840	429.50 429.50	0 0
• BIASED HIGHLY ACCELERATED STRESS TEST +130°C/85% R.H. ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +130°C	NUMBER OF FAILURES
LTM8002	139 139	1817	1840	9.71 9.71	0 0
• UNBIASED HIGHLY ACCELERATED STRESS TEST +130°C/85% R.H. ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +130°C	NUMBER OF FAILURES
LTM8002	231 231	1817	1840	44.35 44.35	0 0

(1) Environmental stress are preceded by J-STD-020 Level 3 Preconditioning